



# Scanning Ion Source IS40 E1

**AES/XPS & SIMS**  
**sample cleaning & preparation**  
**depth profiling**

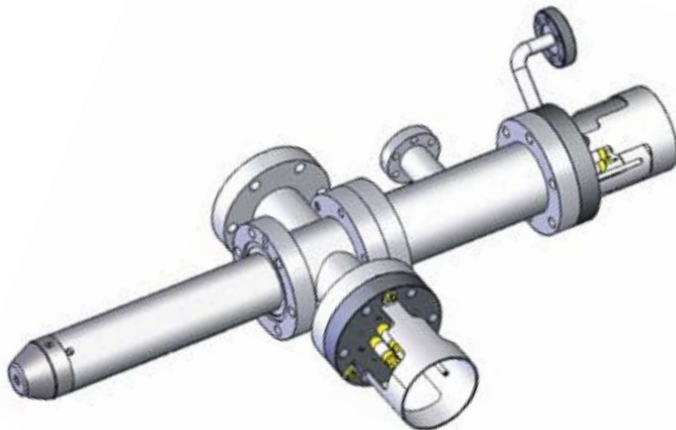
continuously variable spot size  
extremely homogeneous crater/beam profile  
field replaceable low operating temp. filament  
10mm x 10mm scanning area  
0.15keV to 5keV energy range  
UHV gas inlet  
operation with inert & reactive gases (Ar, O<sub>2</sub>, H<sub>2</sub>)  
optional Wien mass filter for elimination of  
unwanted isotopes, multiply charged ions etc.  
software control

# Henniker Scientific

## IS40 Scanning Ion Source

### IS40 Source

Working Distance:	23mm to 100mm		
Spot Size:	150um to 1000um fully variable		
Cone Angle:	50degree		
Insertion Depth:	163mm		
Mounting Flange:	DN-40-CF, rotatable		
High Current Density:	4 mA/cm <sup>2</sup> (6.15uA at 800um spot size)		
Energy Range (E):	0.15keV to 5keV,	resolution	0.01keV
e-Emission Current (Ie):	0.01mA to 10mA,	resolution	0.01mA
Focus Lens (F1, F2):	0 to 5kV,	resolution	1V
Extractor Voltage (Ex):	60 to 99.9% x E,	resolution	0.1%
Beam Position (Px, Py):	-5.0mm to +5mm,	resolution	0.01mm
Scanning Area (Dx, Dy):	0 to 10mm,	resolution	0.01mm
Scan Speed (time/dot):	30us to 30ms		
Timer (dual mode):	0s to 9.99hr		



### IS40 Interface

19 inch Rack Mounting  
Large LCD Front Panel Display with Store & Recall Functions  
Software Interface via RS232/422/485/USB/Bluetooth



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